**Stimulus and Response Solutions** from Agilent Technologies **Pulse Pattern Generators** from Agilent Technologies 1 mHz to 3.35 GHz 15 mV to 100 V



**Agilent Technologies** 

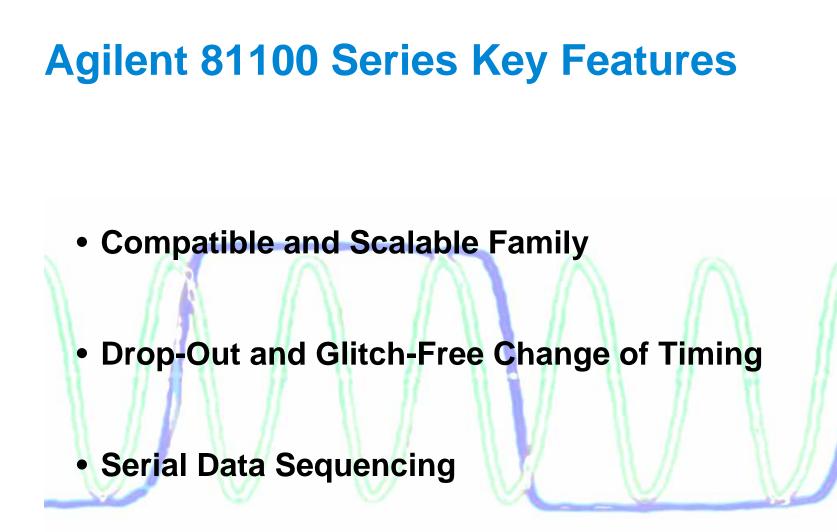
#### **Product Portfolio**

- Entry and Performance Products:
  - 81100 Series: 81101A, 81104A, 81110A, 81130A
    - max. frequency 50 MHz to 660 MHz
- High-End Products:
  - 81133A and 81134A (1/2 channel)
    - 15 MHz to 3.35 GHz
    - Jitter Insertion capability
- Special Application Products:
  - 8114A
    - 100 V amplitude up to 15 MHz





**81100 Series** 



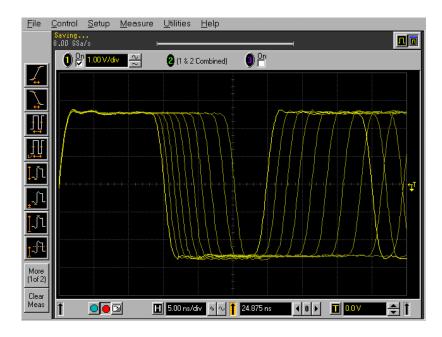


# **Continuous Operation: Drop-out and glitch-free timing changes**

The outputs of the Agilent 81101A, 81104A and 81110A allow to change timing parameters like frequency without creating dropouts or glitches.

This allows a continuous operation without rebooting or resetting the DUT to measure a PLL's pull-in / hold range or to characterize the DUT over clock frequency.

Device example: ABS sensor



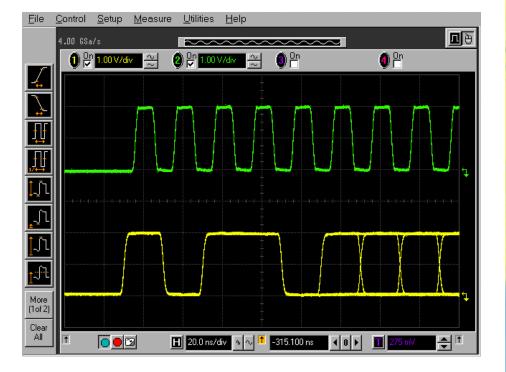


#### Generating arbitrary Data Pattern: Serial data sequencing

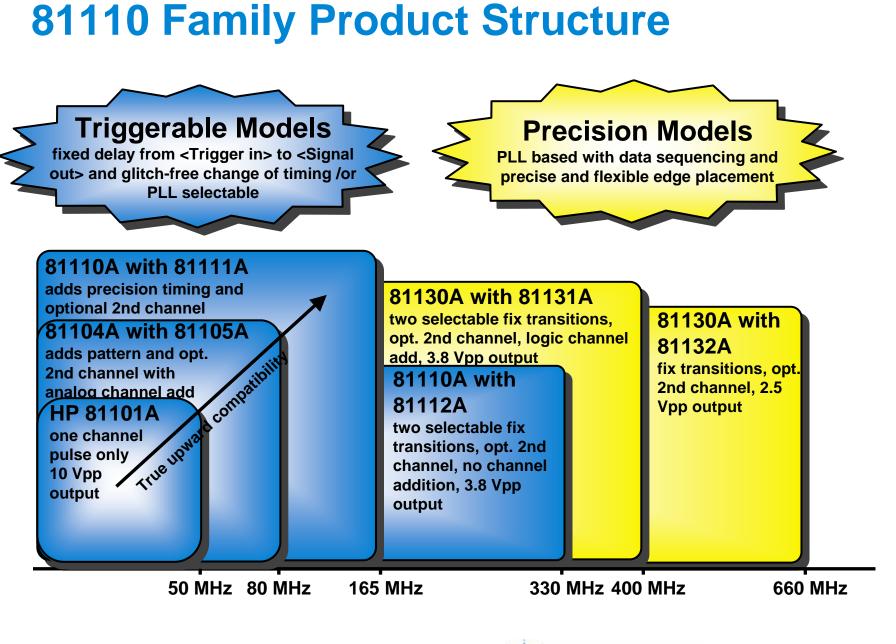
The Agilent 81130A provides powerful data sequencing features, that allow to generate complex data, for example packet data consisting of a header, a PRBS data section and a trailer.

With programming up to 4 segments with the 64 KBit/channel data and one freely placeable loop (count: 1 to 2^20), the 81130A is a powerful data generator.

Segment Length Loopcnt. Update	MODIFY
1 30000	
3 378	1001000
4 800	
MODE\TRG    TIMING    LEVELS	PATTERN







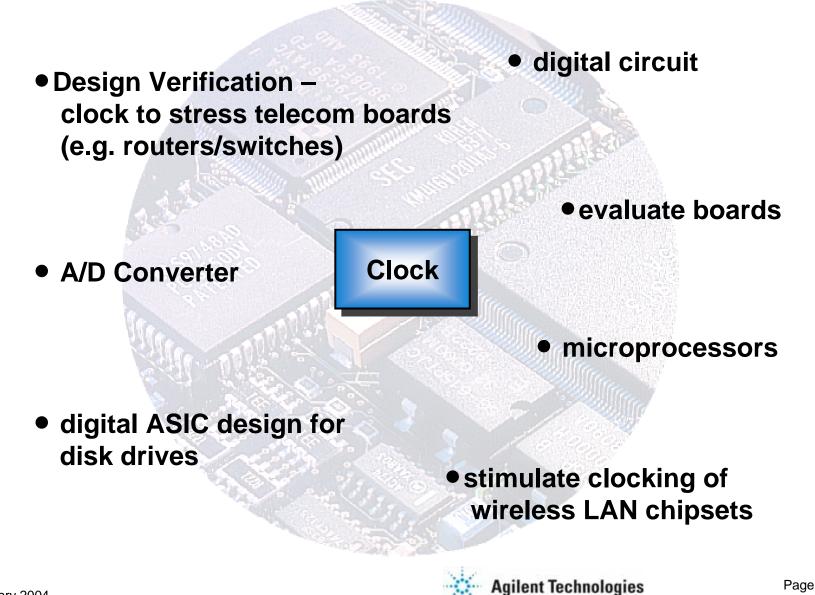
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Pulse Pattern Generators from







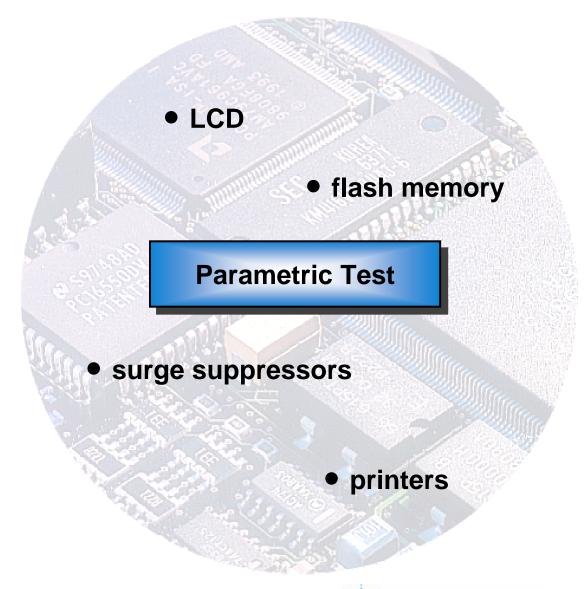
## **Applications**

- simulation of read/write signal for DVD
  - optical card as part of telephone systems airbag explosive sensors flash memory ATE **Functional Test**  amplifiers digital circuits tests surge suppressors disk drives Semiconductor tests

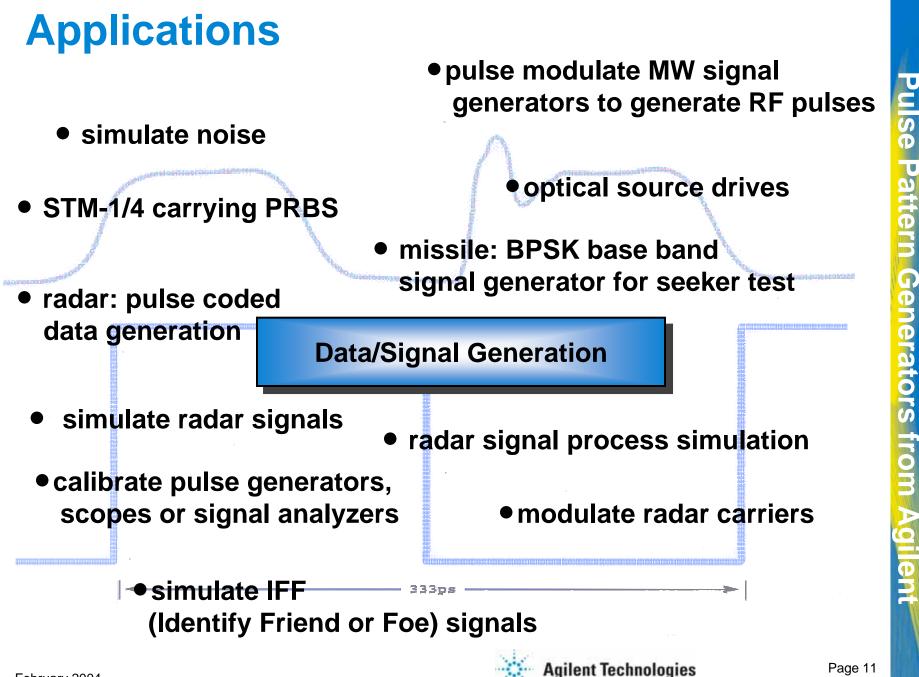
Pulse Pattern Generators from



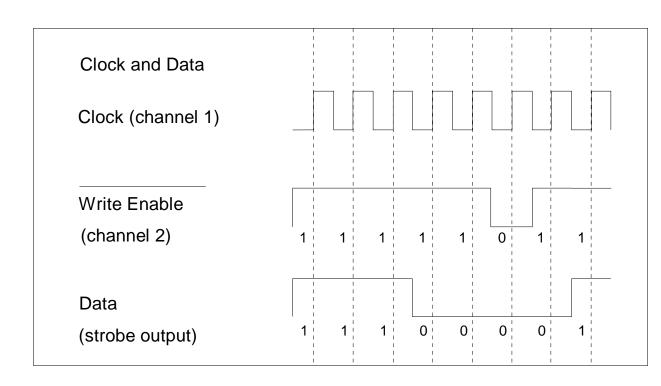
# **Applications**







# Versatile Waveform Generation with pattern- and data-based timing



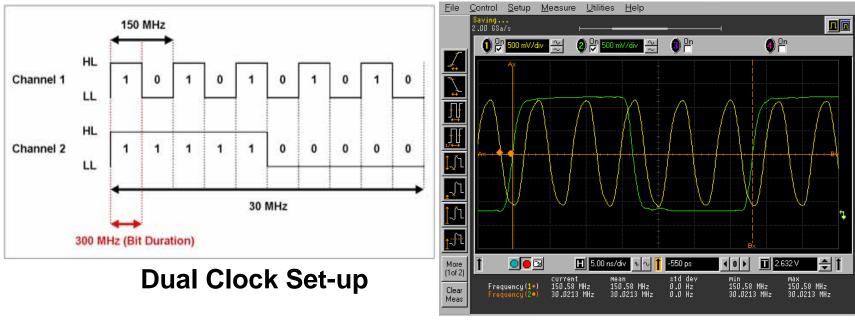
With the 81104A and 81110A, it is possible to generate clock and data signals needed for your application.



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# Versatile Waveform Generation with pattern- and data-based timing

Single, dual or delayed clock signals or up to 16 KBit userdefinable data per channel can be programmed easily

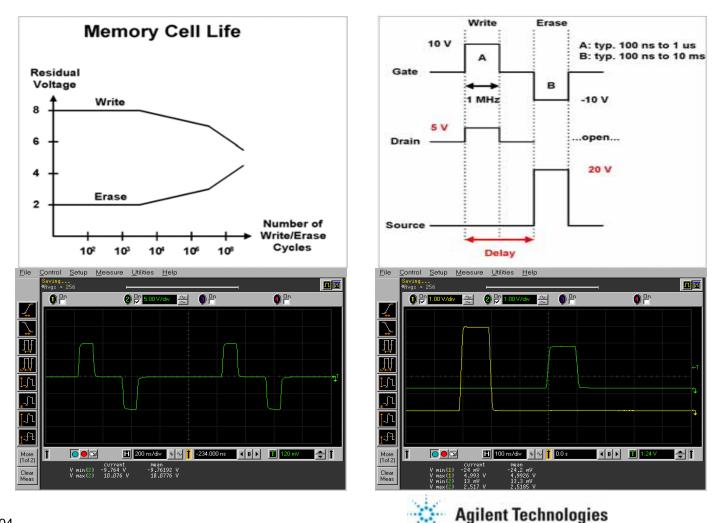


#### Screen Shot of an 150 MHz / 30 MHz dual clock



## Versatile Waveform Generation Channel-add feature

E.g. generating signals for Flash EEprom Tests:



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#### Agilent 81133A / 81134A 3.35 GHz Pulse Pattern Generator



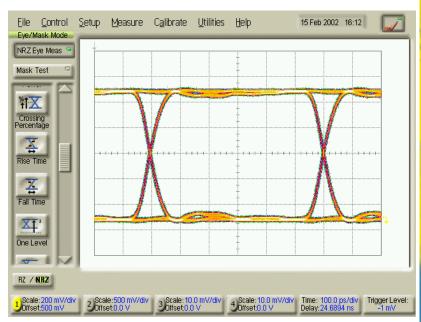
For Applications where Timing, Performance is critical and Control over Signal Quality is required





#### Agilent 81133A / 81134A Overview

- Pulses, pattern and data from 15 MHz to 3.35 GHz
- Ideal when timing and performance is critical
- Test the DUT and not the pulse or data source
- Ideal data- and patternsource for eye diagram measurements







#### Agilent 81133A / 81134A Key Benefits

- Pulses, patterns and data from 15 MHz to 3.35 GHz
- The 81133/34A is an ideal pulse, clock and data source due to its:
  - Fast transition times (60ps for 20-80%)
  - Low intrinsic jitter of less than 2ps (typical)
  - Full parameter flexibility
  - 12 Mbit pattern memory per channel for user defined data
  - PRBS generation with PRBS from 2^5-1 to 2^31-1
  - Delay modulation for easy Jitter injection
  - Deform the 'eye' with the Variable Cross-Over Point
  - Full functionality on all output channels

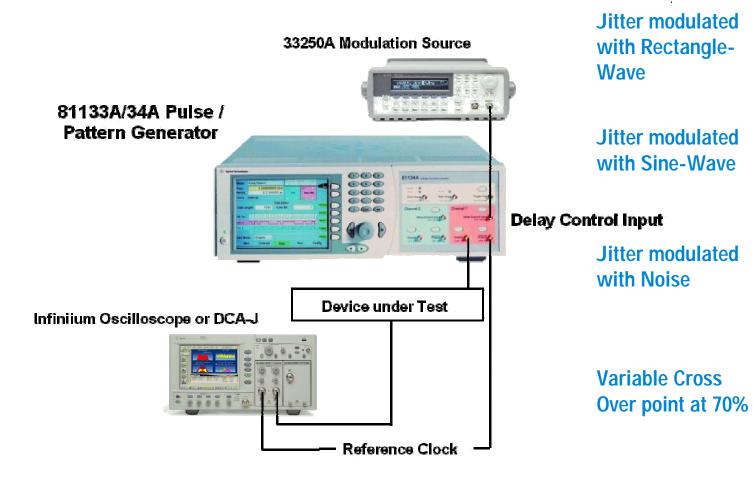


#### Agilent 81133A / 81134A Key Benefits

- The 81133A is a 1 channel configuration, the 81134A provides 2 output channels
- LVDS levels are addressed with output levels from 50 mV to 2 V
- The easy-to-use Graphical User Interface provides access to all necessary parameters
- Remote programming and access via GPIB, LAN and USB 2.0
- Code-compatible with the 8133A Timing Generator



# Jitter Generation and Stressed Eye Diagram Measurements



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**Agilent Technologies** 

# **Applications**

- Jitter generation for Signal Integrity measurements of high-speed digital signals
- Stimulus for serial high-speed bus tests
  - Serial ATA
  - PCI Express
- Disk-drive tests
- Stimulus for a broad range of measurements with
  - Infinitium DCA-J sampling oscilloscopes (86100C family) or
  - Infiniium real-time oscilloscopes (54850A series)

